Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/612,866	KOLEK ET AL.	
Examiner	Art Unit	
Len Tran	1725	

SEARCHED					
Class	Subclass	Date	Examiner		
164	444	6/29/2005	LT		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH I (INCLUDING SEAR)
	DATE	EXMR
, palm	6/29/2005	LT
164/ 444 (US Patent)	6/29/2005	LT
text search (attach printout)	6/29/2005	LT